

Reverse Breakdown

- *2 Mechanisms:*

- *Zener*

- *Avalanche*

- *Zener:*

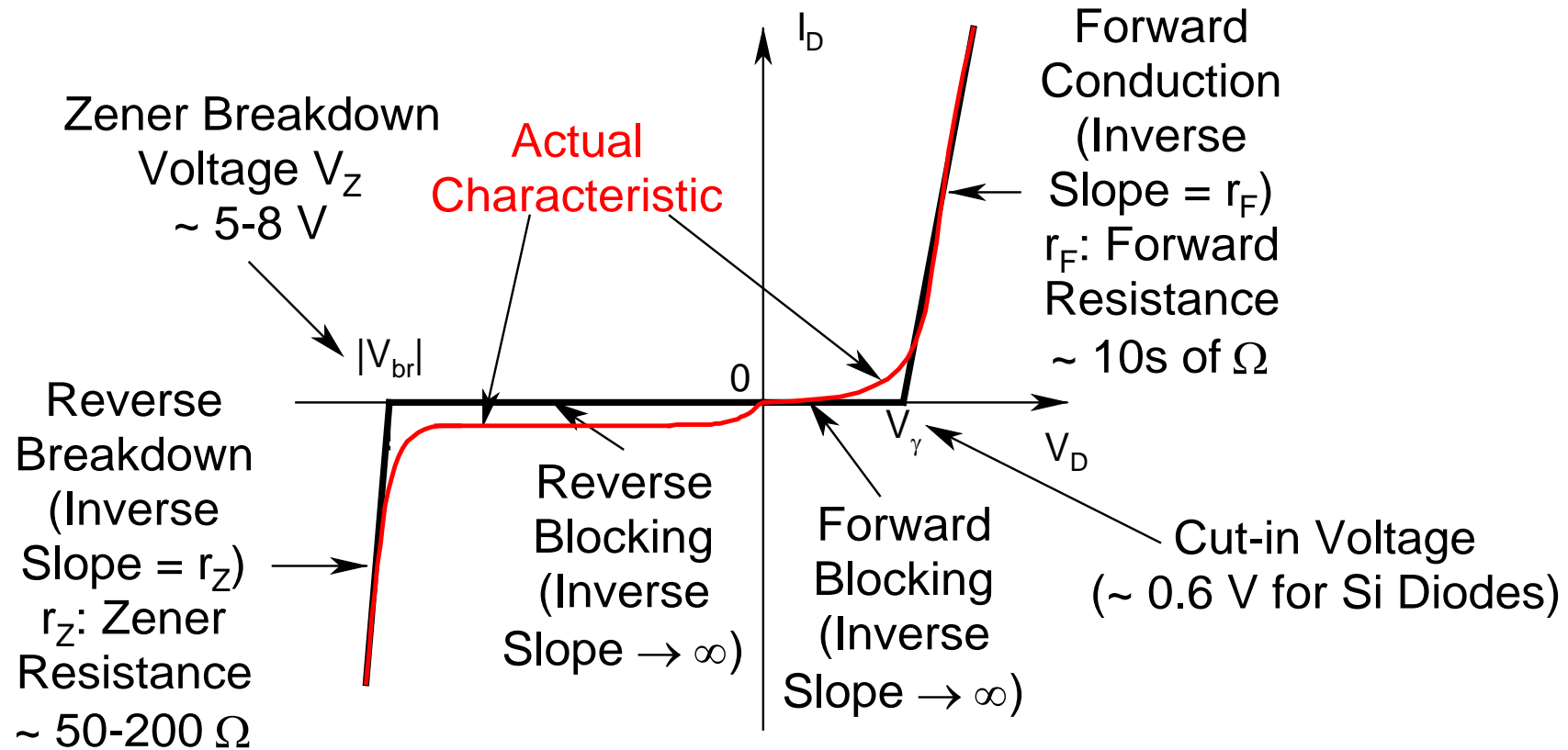
- *For junctions with both sides very heavily doped*

- *Thin depletion region*, through which carriers *tunnel through* (*quantum mechanical process*)

- *Typical $|V_{br}| < 3 V$*

- *Avalanche:*
 - *Classical breakdown process*
 - *At least one side must be lightly doped*
 - *Carrier multiplication* due to *impact ionization*
 - *Typical $|V_{br}| > 5\text{ V}$*
- For diodes having $|V_{br}|$ *in between 3 V and 5 V*, *a combination of these two processes*
- *Breakdowns* are generally *destructive*, unless the *current* is *controlled* by *external means*, e.g., by a *resistor*

Piece-Wise Linear (PWL) Model



Note: The forward and reverse current scales are not same

PWL Regions

- $0 \leq V_D \leq V_\gamma$: *Forward Blocking*
 - V_γ : *Cut-in Voltage* (~ 0.6 V for Si diodes)
 - $I_D = 0$
- $V_D \geq V_\gamma$: *Forward Conduction*
 - I_D increases linearly with V_D with an *inverse slope of r_F*
 - r_F : *Diode Forward Resistance* (~ 10 s of Ω)
 $= [dI_D/dV_D]^{-1}$

- Diodes under *forward bias* and for $V_D \geq V_\gamma$, offer *small resistance* (results from the *exponential* I-V characteristic)
- V_D negative and $0 \leq |V_D| \leq |V_{br}|$: *Reverse Blocking*
 - $I_D = 0$
- V_D negative and $|V_D| \geq |V_{br}|$: *Reverse Breakdown*
 - $|I_D|$ increases linearly with $|V_D|$ with an *inverse slope of r_Z*

- r_Z : **Zener Resistance** ($\sim 50\text{-}200\ \Omega$)
 $= [d|I_D|/d|V_D|]^{-1}$
- Diodes under **reverse bias** and for $|V_D| \geq |V_{br}|$, offer **small resistance**
 \Rightarrow **If current is not controlled by external means, then it may damage the device completely**
 - Generally, diodes, unless they are to be operated in **breakdown mode**, e.g., in a **voltage regulator**, have **very high** $|V_{br}|$, typically of the order of **100s of V**